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Kind regards,

Team Nexperia

BUK7506-55B

N-channel TrenchMOS standard level FET

Rev. 02 — 21 June 2010

Product data sheet

1. Product profile

1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Q101 compliant

- Suitable for standard level gate drive sources
- Suitable for thermally demanding environments due to 175 °C rating

1.3 Applications

- 12 V and 24 V loads
- Automotive systems
- General purpose power switching
- Motors, lamps and solenoids



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N-channel TrenchMOS standard level FET

1.4 Quick reference data

Table 1. Quick reference data

	·						
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$		-	-	55	V
I _D	drain current	V _{GS} = 10 V; T _{mb} = 25 °C; see <u>Figure 1</u> ; see <u>Figure 3</u>	<u>[1]</u>	-	-	75	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	-	254	W
Static chara	acteristics						
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 11}{\text{Figure } 12};$ see Figure 12		-	5.1	6	mΩ
Avalanche	ruggedness						
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$I_D = 75 \text{ A}; V_{sup} \le 55 \text{ V};$ $R_{GS} = 50 \Omega; V_{GS} = 10 \text{ V};$ $T_{j(init)} = 25 ^{\circ}C; unclamped$		-	-	680	mJ
Dynamic ch	naracteristics						
Q_{GD}	gate-drain charge	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $V_{DS} = 44 \text{ V}; T_j = 25 \text{ °C};$ see Figure 13		-	19	-	nC

^[1] Continuous current is limited by package.

Pinning information

Table 2. **Pinning information**

		,		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		
2	D	drain	mb	D
3	S	source		$_{G}$
mb	D	mounting base; connected to drain	1 2 3	mbb076 S
			SOT78A (TO-220AB)	

Ordering information

Table 3. **Ordering information**

Type number	Package		
	Name	Description	Version
BUK7506-55B	TO-220AB	plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78A

4. Limiting values

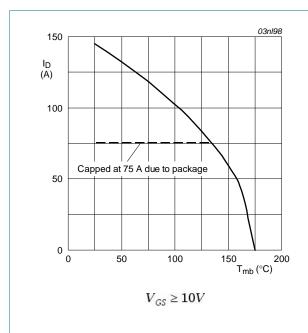
Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Parameter	Conditions		Min	Тур	Max	Unit
drain-source voltage	T _i ≥ 25 °C; T _i ≤ 175 °C		-	-	55	٧
drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$		-	-	55	V
gate-source voltage			-20	-	20	٧
drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 3</u> ; see <u>Figure 1</u>	<u>[1]</u>	-	-	145	Α
	$T_{mb} = 100 ^{\circ}\text{C}; V_{GS} = 10 \text{V}; \text{see} \frac{\text{Figure 1}}{\text{Constant}}$	[2]	-	-	75	Α
	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u> ; see <u>Figure 3</u>	[2]	-	-	75	Α
peak drain current	T_{mb} = 25 °C; t_p ≤ 10 μs; pulsed; see Figure 3		-	-	582	Α
total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	-	254	W
storage temperature			-55	-	175	°C
junction temperature			-55	-	175	°C
diode						
source current	T _{mb} = 25 °C	<u>[1]</u>	-	-	145	Α
		[2]	-	-	75	Α
peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$		-	-	582	Α
ggedness						
non-repetitive drain-source avalanche energy	I_D = 75 A; V_{sup} ≤ 55 V; R_{GS} = 50 Ω; V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; unclamped		-	-	680	mJ
	drain-source voltage drain-gate voltage gate-source voltage drain current peak drain current total power dissipation storage temperature junction temperature diode source current peak source current ggedness non-repetitive drain-source	$\begin{array}{lll} & \text{drain-source voltage} & T_{j} \geq 25 \ ^{\circ}\text{C}; \ T_{j} \leq 175 \ ^{\circ}\text{C} \\ & \text{drain-gate voltage} & R_{GS} = 20 \ \text{k}\Omega \\ & \text{gate-source voltage} \\ & \text{drain current} & T_{mb} = 25 \ ^{\circ}\text{C}; \ \text{V}_{GS} = 10 \ \text{V}; \ \text{see } \underline{\text{Figure } 3}; \\ & \text{see } \underline{\text{Figure } 1} \\ & T_{mb} = 100 \ ^{\circ}\text{C}; \ \text{V}_{GS} = 10 \ \text{V}; \ \text{see } \underline{\text{Figure } 1}; \\ & \text{See } \underline{\text{Figure } 3} \\ & \text{peak drain current} & T_{mb} = 25 \ ^{\circ}\text{C}; \ \text{V}_{GS} = 10 \ \text{V}; \ \text{see } \underline{\text{Figure } 1}; \\ & \text{see } \underline{\text{Figure } 3} \\ & \text{total power dissipation} & T_{mb} = 25 \ ^{\circ}\text{C}; \ \text{tp} \leq 10 \ \text{\mus}; \ \text{pulsed}; \\ & \text{see } \underline{\text{Figure } 2} \\ & \text{storage temperature} \\ & \text{junction temperature} \\ & \text{diode} \\ & \text{source current} & T_{mb} = 25 \ ^{\circ}\text{C} \\ & \text{peak source current} & T_{p} \leq 10 \ \text{\mus}; \ \text{pulsed}; \ T_{mb} = 25 \ ^{\circ}\text{C} \\ & \text{ggedness} \\ & \text{non-repetitive} & I_{D} = 75 \ \text{A}; \ \text{V}_{\text{sup}} \leq 55 \ \text{V}; \ \text{R}_{GS} = 50 \ \Omega; \\ & \text{V}_{GS} = 10 \ \text{V}; \ T_{j(\text{init})} = 25 \ ^{\circ}\text{C}; \ \text{unclamped} \\ \end{array}$	$\begin{array}{lll} drain\text{-source voltage} & T_j \geq 25 \ ^\circ\text{C}; \ T_j \leq 175 \ ^\circ\text{C} \\ \\ drain\text{-gate voltage} & R_{GS} = 20 \ \text{k}\Omega \\ \\ gate\text{-source voltage} \\ \\ drain \ current & T_{mb} = 25 \ ^\circ\text{C}; \ V_{GS} = 10 \ \text{V}; \ see \ \underline{Figure \ 3}; & 11 \\ \hline T_{mb} = 100 \ ^\circ\text{C}; \ V_{GS} = 10 \ \text{V}; \ see \ \underline{Figure \ 1}; & 22 \\ \hline T_{mb} = 25 \ ^\circ\text{C}; \ V_{GS} = 10 \ \text{V}; \ see \ \underline{Figure \ 1}; & 22 \\ \hline Figure \ 3 & 25 \ ^\circ\text{C}; \ V_{GS} = 10 \ \text{V}; \ see \ \underline{Figure \ 1}; & 23 \\ \hline peak \ drain \ current & T_{mb} = 25 \ ^\circ\text{C}; \ t_p \leq 10 \ \mu\text{s}; \ pulsed; \\ see \ \underline{Figure \ 3} & 25 \ ^\circ\text{C}; \ see \ \underline{Figure \ 2} \\ \hline total \ power \ dissipation & T_{mb} = 25 \ ^\circ\text{C}; \ see \ \underline{Figure \ 2} \\ \hline storage \ temperature & 100000000000000000000000000000000000$	$\begin{array}{llllllllllllllllllllllllllllllllllll$	$\begin{array}{llllllllllllllllllllllllllllllllllll$	$\begin{array}{cccccccccccccccccccccccccccccccccccc$

^[1] Current is limited by power dissipation chip rating.

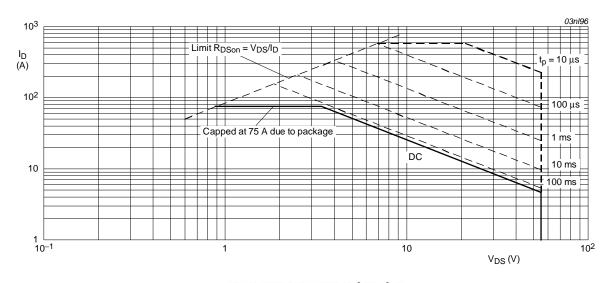
^[2] Continuous current is limited by package.



03na19 120 P_{der} (%) 80 40 0 0 100 150 200 T_{mb} (°C) $P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$

Normalized continuous drain current as a function of mounting base temperature

Normalized total power dissipation as a Fig 2. function of mounting base temperature



 $T_{mb} = 25$ °C; I_{DM} is single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	0.59	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	vertical in still air	-	-	60	K/W

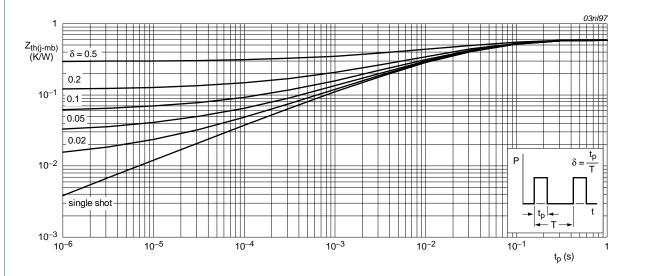


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

6. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static char	acteristics					
V _{(BR)DSS}	drain-source	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	55	-	-	V
	breakdown voltage	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55 \text{ °C}$	50	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = -55$ °C; see <u>Figure 10</u>	-	-	4.4	V
		I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 25 °C; see <u>Figure 10</u>	2	3	4	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 175$ °C; see <u>Figure 10</u>	1	-	-	V
I _{DSS}	drain leakage current	$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.02	1	μΑ
		V _{DS} = 55 V; V _{GS} = 0 V; T _i = 175 °C	-	-	500	μΑ
I _{GSS}	gate leakage current	V _{DS} = 0 V; V _{GS} = 20 V; T _i = 25 °C	-	2	100	nA
		V _{DS} = 0 V; V _{GS} = -20 V; T _i = 25 °C	-	2	100	nA
R _{DSon}	drain-source on-state resistance	V _{GS} = 10 V; I _D = 25 A; T _j = 175 °C; see <u>Figure 11</u> ; see <u>Figure 12</u>	-	-	12	mΩ
		V_{GS} = 10 V; I_D = 25 A; T_j = 25 °C; see Figure 11; see Figure 12	-	5.1	6	mΩ
Dynamic c	haracteristics					
Q _{G(tot)}	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 44 \text{ V}; V_{GS} = 10 \text{ V};$	-	64	-	nC
Q _{GS}	gate-source charge	T _j = 25 °C; see <u>Figure 13</u>	-	14	-	nC
Q _{GD}	gate-drain charge		-	19	-	nC
C _{iss}	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$	-	3825	5100	pF
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 14</u>	-	783	940	pF
C _{rss}	reverse transfer capacitance		-	235	322	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 30 \text{ V}; R_L = 1.2 \Omega; V_{GS} = 10 \text{ V}; R_{G(ext)} = 10 \Omega; T_j = 25 ^{\circ}\text{C}$	-	30	-	ns
t _r	rise time	$V_{DS} = 30 \text{ V}; R_L = 1.2 \Omega; V_{GS} = 10 \text{ V}; R_{G(ext)} = 10 \Omega; T_j = 30 \text{ °C}$	-	46	-	ns
t _{d(off)}	turn-off delay time	$V_{DS} = 30 \text{ V}; R_L = 1.2 \Omega; V_{GS} = 10 \text{ V};$	-	85	-	ns
t _f	fall time	$R_{G(ext)} = 10 \Omega$; $T_j = 25 °C$	-	39	-	ns
L _D	internal drain inductance	from contact screw on mounting base to centre of die; $T_j = 25$ °C	-	3.5	-	nΗ
		from drain lead 6 mm from package to centre of die; T _j = 25 °C	-	4.5	-	nΗ
L _S	internal source inductance	from source lead to source bond pad ; $T_j = 25 ^{\circ}\text{C}$	-	7.5	-	nΗ
Source-dra	ain diode					
V _{SD}	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C};$ see <u>Figure 15</u>	-	0.85	1.2	V
	reverse recovery time	$I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s};$	-	73	-	ns
t _{rr}		$V_{GS} = -10 \text{ V}; V_{DS} = 30 \text{ V}; T_i = 25 \text{ °C}$				

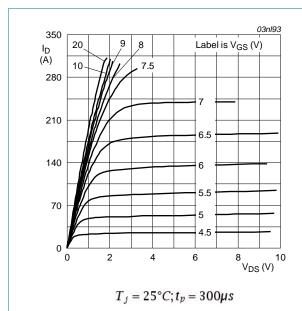
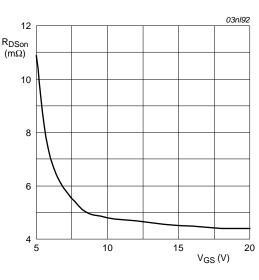


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values



 $T_j=25^{\circ}C; I_D=25A$

Fig 6. Drain-source on-state resistance as a function of gate-source voltage; typical values

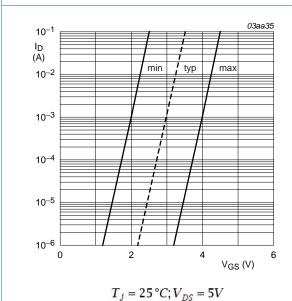


Fig 7. Sub-threshold drain current as a function of gate-source voltage

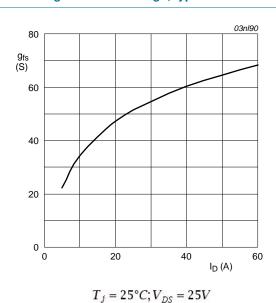


Fig 8. Forward transconductance as a function of drain current; typical values

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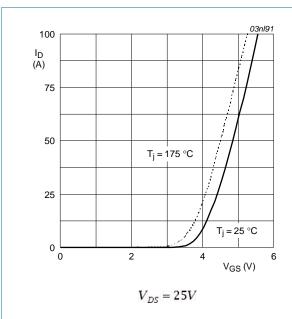


Fig 9. Transfer characteristics: drain current as a function of gate-source voltage; typical values

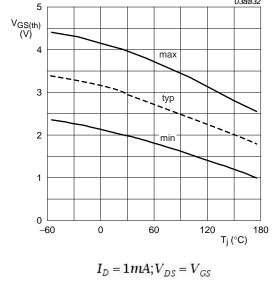


Fig 10. Gate-source threshold voltage as a function of junction temperature

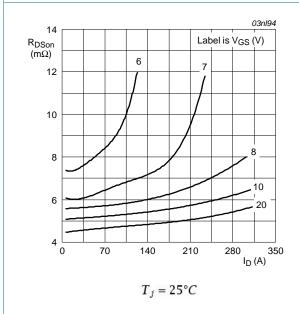


Fig 11. Drain-source on-state resistance as a function of drain current; typical values

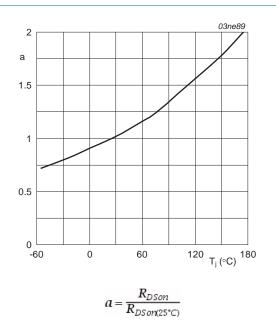


Fig 12. Normalized drain-source on-state resistance factor as a function of junction temperature

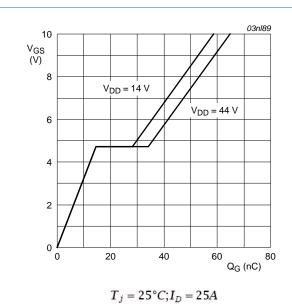
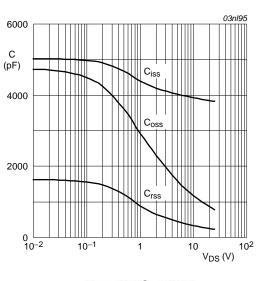


Fig 13. Gate-source voltage as a function of turn-on gate charge; typical values



 $V_{GS} = 0V; f = 1MHz$

Fig 14. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

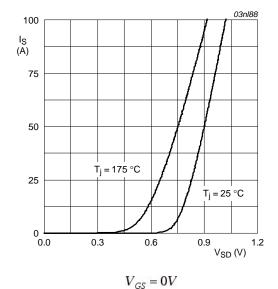
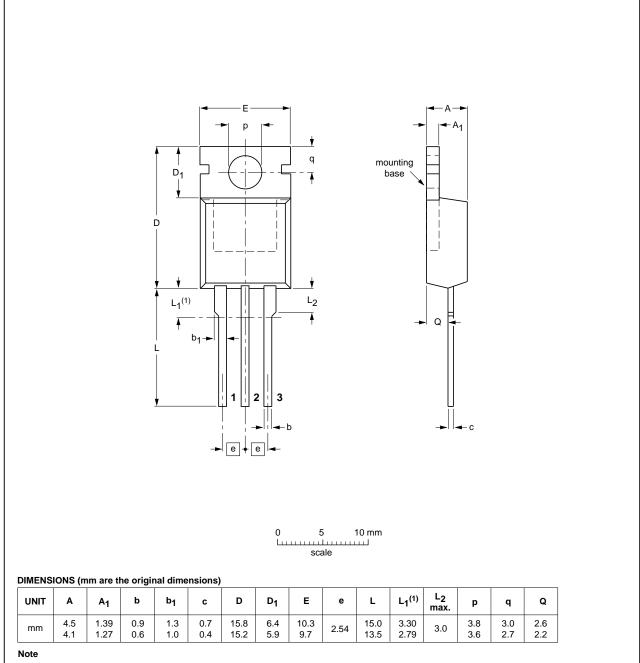


Fig 15. Source current as a function of source-drain voltage; typical values

7. Package outline

Plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB

SOT78A



1. Terminals in this zone are not tinned.

OUTLINE VERSION		REFER	ENCES	EUROPEAN	ISSUE DATE
	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT78A		3-lead TO-220AB	SC-46		03-01-22 05-03-14

Fig 16. Package outline SOT78A (TO-220AB)

BUK7506-55B

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8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes	
BUK7506-55B v.2	20100621	Product data sheet	-	BUK75_7606_55B v.1	
Modifications:	 The format of this data sheet has been redesigned to comply with the new identity guideline of NXP Semiconductors. 				
	 Legal texts 	have been adapted to the	e new company name wh	nere appropriate.	
	 Type numb 	er BUK7506-55B separat	ed from data sheet BUK7	75_7606_55B v.1.	
BUK75_7606_55B v.1	20030331	Product data sheet	-	-	

9. Legal information

9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions'
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BUK7506-55B

N-channel TrenchMOS standard level FET

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